

-200V P-Channel Enhancement Mode MOSFET

Description

The AP9P20P/T uses advanced trench technology to provide excellent $R_{DS(ON)}$, low gate charge and operation with gate voltages as low as 10V. This device is suitable for use as a Battery protection or in other Switching application.

General Features

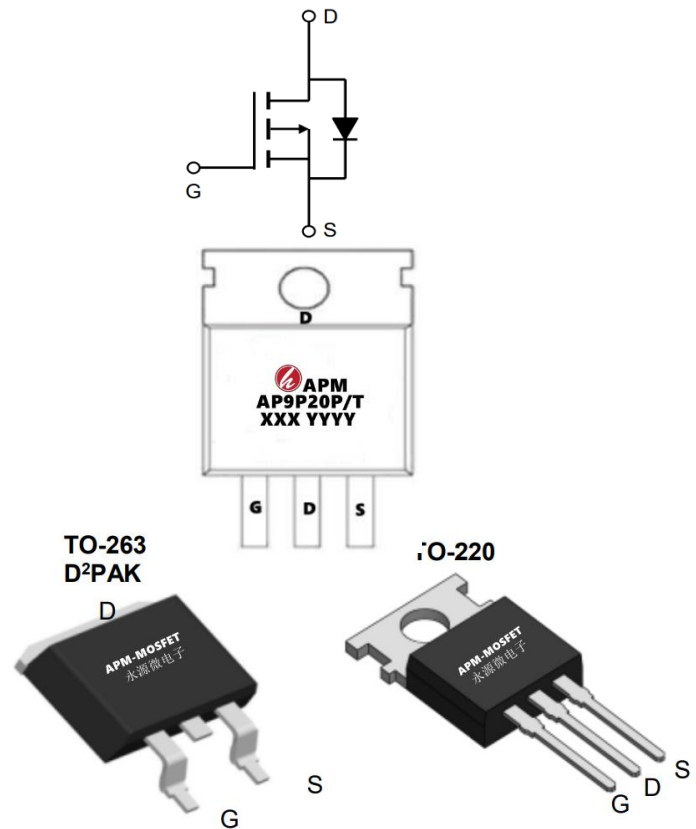
$V_{DS} = -200V$ $I_D = -9.0A$

$R_{DS(ON)} < 750m\Omega$ @ $V_{GS} = -10V$ (Type: 625m Ω)

Application

Lithium battery protection

Mobile phone fast charging



Package Marking and Ordering Information

Product ID	Pack	Marking	Qty(PCS)
AP9P20P	TO-220-3L	AP9P20P XXX YYYY	2500
AP9P20T	TO-263-3L	AP9P20T XXX YYYY	4000

Absolute Maximum Ratings ($T_C = 25^\circ C$ unless otherwise noted)

Symbol	Parameter	Rating	Units
V_{DS}	Drain-Source Voltage	- 200	V
V_{GS}	Gate-Source Voltage	± 20	V
$I_D @ T_C = 25^\circ C$	Continuous Drain Current, $-V_{GS} @ -10V^1$	-8.7	A
$I_D @ T_C = 100^\circ C$	Continuous Drain Current, $-V_{GS} @ -10V^1$	-3.6	A
I_{DM}	Pulsed Drain Currenta	- 22.8	A
EAS	Single Pulse Avalanche Energyb	570	mJ
IAR	Repetitive Avalanche Currenta	-8.7	A
EAR	Repetitive Avalanche Energya	5.5	mJ
PD	Maximum Power Dissipation $T_C = 25^\circ C$	55	W
dV/dt	Peak Diode Recovery dV/dtc	- 5.5	V/ns
T_J, T_{stg}	Operating Junction and Storage Temperature Range	- 55 to + 150	$^\circ C$
R_{thJA}	Maximum Junction-to-Ambient	62.5	$^\circ C/W$
R_{thJC}	Maximum Junction-to-Case (Drain)	2.2	$^\circ C/W$

-200V P-Channel Enhancement Mode MOSFET

Electrical Characteristics (T_J=25°C, unless otherwise noted)

Symbol	Parameter	Conditions	Min.	Typ.	Max.	Unit
BVDSS	Drain-Source Breakdown Voltage	V _{GS} =0V, I _D =-250μA	-200	-230	---	V
ΔBVDSS/ΔT _J	BV _{DSS} Temperature Coefficient	Reference to 25°C, I _D =-1mA	---	-0.035	---	V/°C
RDS(ON)	Static Drain-Source On-Resistance ²	V _{GS} =-10V, I _D =-20A	---	625	750	mΩ
VGS(th)	Gate Threshold Voltage	V _{GS} =V _{DS} , I _D =-250μA	-2.0	-3.0	-4.0	V
ΔVGS(th)	V _{GS(th)} Temperature Coefficient		---	4.28	---	mV/°C
IDSS	Drain-Source Leakage Current	V _{DS} =-60V, V _{GS} =0V, T _J =25°C	---	---	1	μA
		V _{DS} =-60V, V _{GS} =0V, T _J =55°C	---	---	5	
IGSS	Gate-Source Leakage Current	V _{GS} =±20V, V _{DS} =0V	---	---	±100	nA
gfs	Forward Transconductance	V _{DS} =-50V, I _D =-2.2A	---	18	---	S
Q _g	Total Gate Charge (-4.5V)	I _D =-7.3A, V _{DS} =-160V V _{GS} =-10V	---	20	---	nC
Q _{gs}	Gate-Source Charge		---	3.3	---	
Q _{gd}	Gate-Drain Charge		---	11	---	
Td(on)	Turn-On Delay Time	VDD=-100V, I _D =-7.3A, RG=18 Ω, RD=25Ω,	---	8.8	---	ns
T _r	Rise Time		---	27	---	
Td(off)	Turn-Off Delay Time		---	7.3	---	
T _f	Fall Time		---	19	---	
C _{iss}	Input Capacitance	V _{GS} =0V, V _{DS} =-25V, f=1.0MHz,	---	590	---	pF
C _{oss}	Output Capacitance		---	140	---	
C _{rss}	Reverse Transfer Capacitance		---	25	---	
I _S	Continuous Source Current ^{1,5}	V _G =V _D =0V, Force Current	---	---	-9.0	A
ISM	Pulsed Source Current ^{2,5}		---	---	-27	A
VSD	Diode Forward Voltage ²	V _{GS} =0V, I _S =-1A, T _J =25°C	---	---	-1.2	V

Note :

- 1、The data tested by surface mounted on a 1 inch 2 FR-4 board with 20Z copper.
- 2、The data tested by pulsed , pulse width ≤ 300us , duty cycle ≤ 2%
- 3、The EAS data shows Max. rating . The test condition is VDD =-48V,VGS =-10V,L=0.1mH,IAS =-82A
- 4、The power dissipation is limited by 150°C junction temperature
- 5、The data is theoretically the same as I D and I DM , in real applications , should be limited by total power dissipation.

-200V P-Channel Enhancement Mode MOSFET

Typical Characteristics

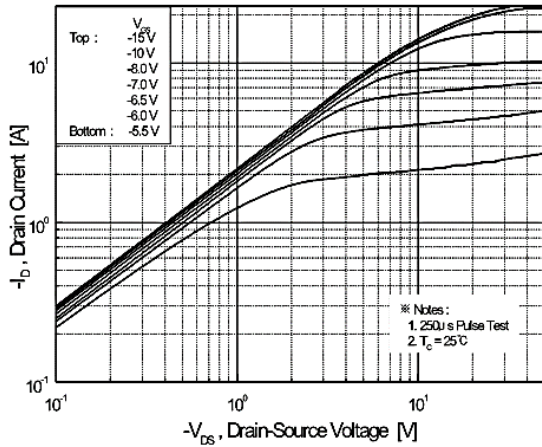


Figure 1. On-Region Characteristics

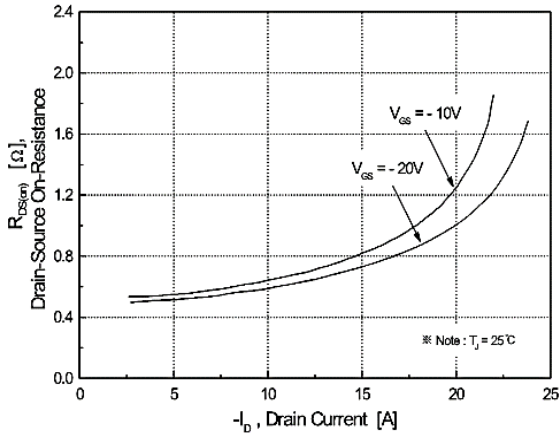


Figure 3. On-Resistance Variation vs. Drain Current and Gate Voltage

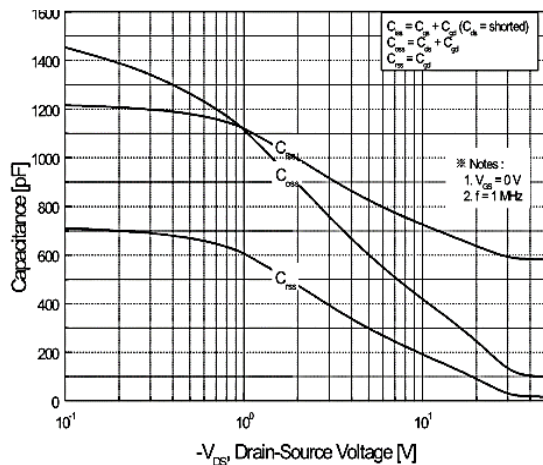


Figure 5. Capacitance Characteristics

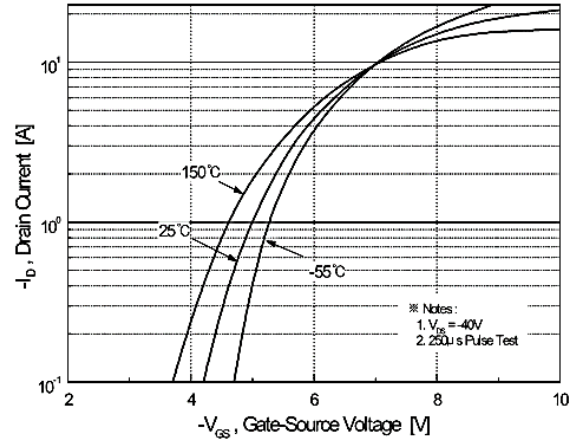


Figure 2. Transfer Characteristics

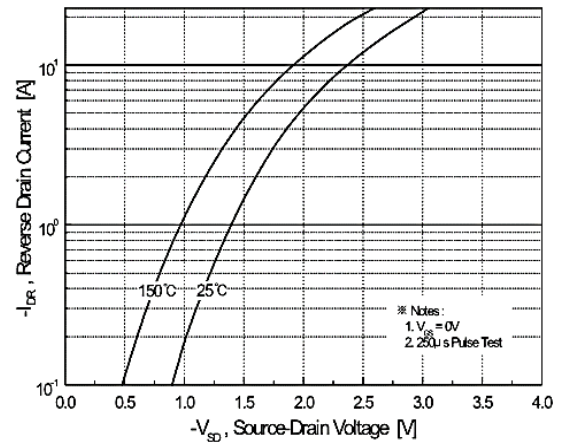


Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperature

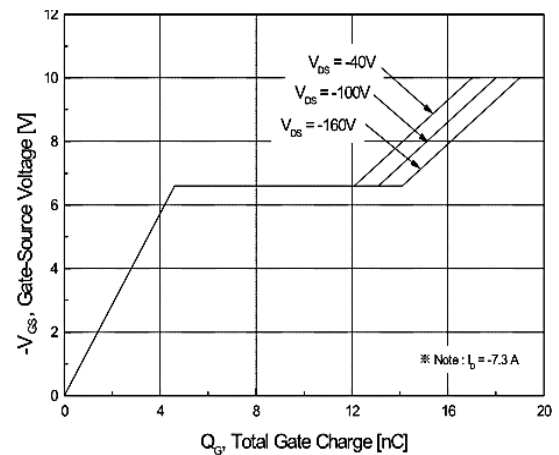


Figure 6. Gate Charge Characteristics

-200V P-Channel Enhancement Mode MOSFET

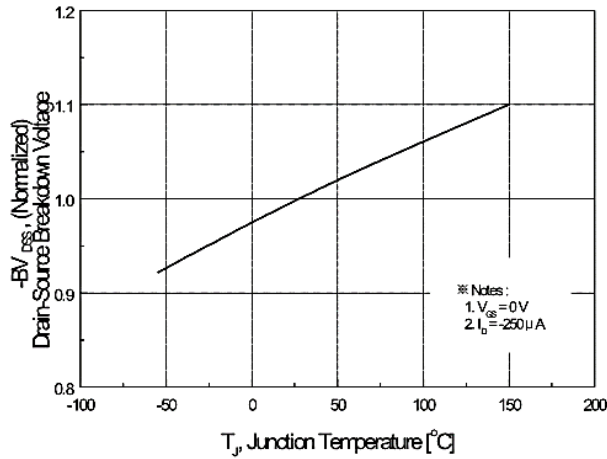


Figure 7. Breakdown Voltage Variation vs. Temperature

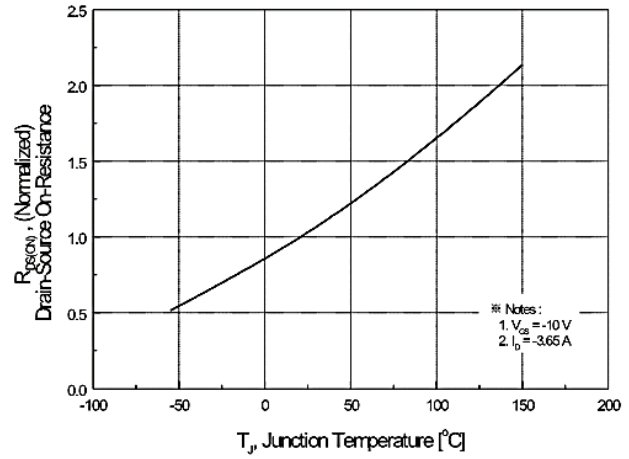


Figure 8. On-Resistance Variation vs. Temperature

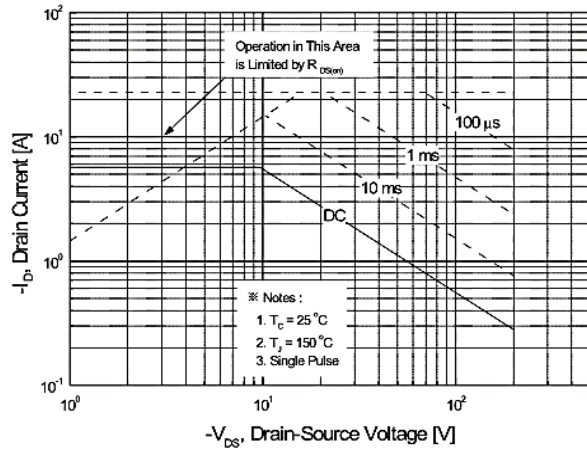


Figure 9. Maximum Safe Operating Area

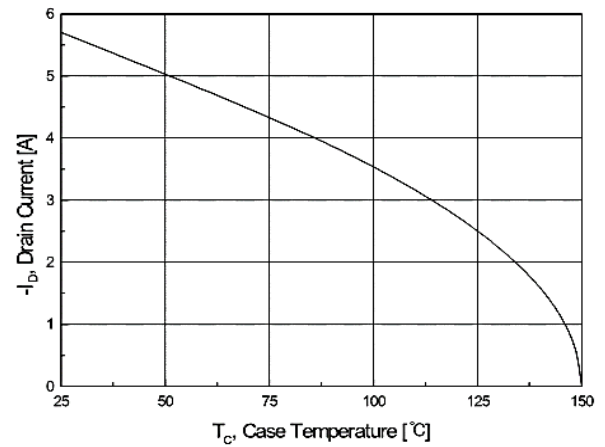


Figure 10. Maximum Drain Current vs. Case Temperature

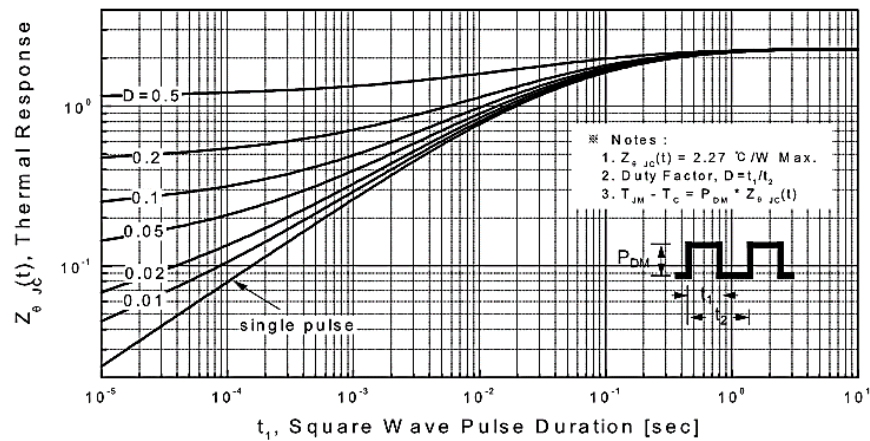
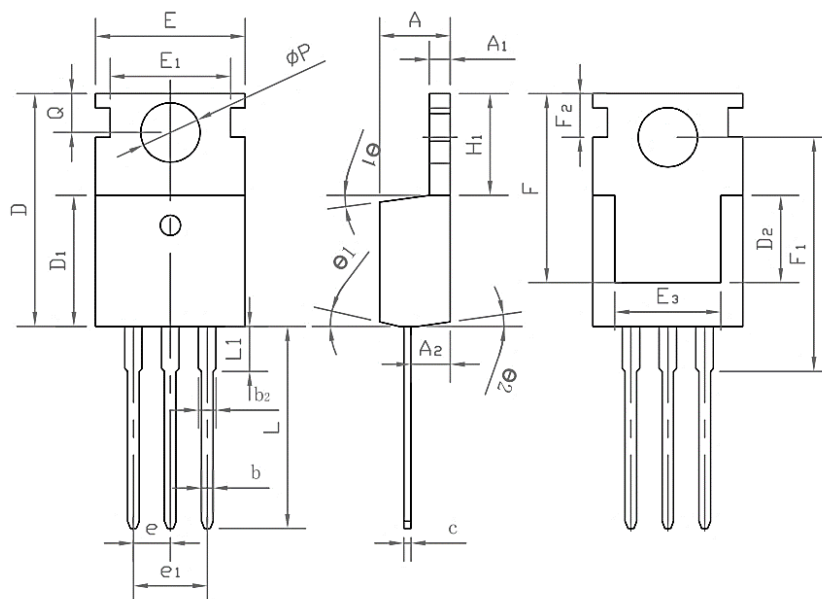


Figure 11. Transient Thermal Response Curve

-200V P-Channel Enhancement Mode MOSFET

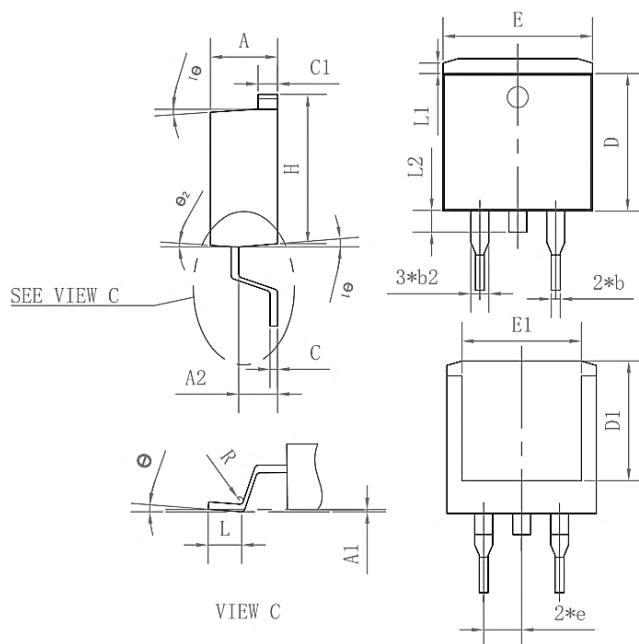
Package Mechanical Data-TO-220-3L-SLK



Symbol	Common		
	mm		
	Mim	Nom	Max
A	4.27	4.57	4.87
A1	1.15	1.30	1.45
A2	2.10	2.40	2.70
b	0.70	0.80	1.00
b2	1.17	1.27	1.50
D	0.40	0.50	0.65
D1	8.80	9.10	9.40
D2	5.70	6.70	7.00
E	9.70	10.00	10.30
E1	-	8.70	-
E2	9.63	10.00	10.35
E3	7.00	8.00	8.40
e	0.37		
e1	0.10		
H1	6.00	6.50	6.85
L	12.75	13.50	13.90
L1	-	3.10	3.40
Φp	3.45	3.60	3.75
Q	2.60	2.80	3.00
θ1	4°	7°	10°
θ2	0°	3°	6°
F	13.30	13.50	13.70
F1	15.50	15.90	16.30
F2	2.80	3.00	3.20

-200V P-Channel Enhancement Mode MOSFET

Package Mechanical Data-TO-263-3L-SLK



Symbol	Common		
	Mim	Nom	Max
A	4.35	4.47	4.60
A1	0.09	0.10	0.11
A2	2.30	2.40	2.70
b	0.70	0.80	1.00
b2	1.25	1.36	1.50
C	0.45	0.50	0.65
C1	1.29	1.30	9.40
D	9.10	9.20	9.30
D1	7.90	8.00	8.10
E	9.85	10.00	10.20
E1	7.90	8.00	8.10
H	15.30	15.50	15.70
e	-	2.54	-
L	2.34	2.54	2.74
L1	1.00	1.10	1.20
L2	1.30	1.40	1.50
R	0.24	0.25	0.26
θ	0°	4°	8°
θ1	4°	7°	10°
θ2	0°	3°	6°

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Edition	Date	Change
REV1.0	2023/1/31	Initial release

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